

Search Notes

Application/Control No.

10/657,100

Examiner

Khai M. Nguyen

Applicant(s)/Patent under
Reexamination

ARAKAWA, TAKEHARU

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	566 550.1 422.1 73 457 414.1 414.3	3/23/2006	KN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see attached)	3/23/2006	kn